## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		PTVS64VS1UR-Q Part Description						
								Nexperia DHAM
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC Preconditioning	Soak Tamb = 85 °C, RH = 85% Reflow soldering	168 hours 3 cycles	120	24622	•		
# A1	Freconditioning	-	J LYLIES	438	24630	0		
	HTRB	MIL-STD-750-1 M1038 Method A						
		Tj = Tjmax, Vr = $100\%$ of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	166	10040	0		
# DI			1000 110013	100	10010	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	131	7760	0		
	UHAST	JESD22-A118						
# A3 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %	— 96 hours	131	7760	0		
		JESD22-A102	50 110013					
	AC	Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
		150000 4141						
	H3TRB	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of						
# AD -1	High Humidity High Temperature Reverse Bias		1000 have	1.21	7760	0		
# A2 alt	remperature Reverse blas		1000 hours	131	7760	0		
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta T_j$ =						
# A5	Intermittent Operating Life		1000 hours	n.a.	n.a.	n.a.		
			1000 110013			a.		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	45	1350	0		
	SD			-		-		
# C10	Solderability	J-STD-002		111	1110	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Protection	10040	0	0,42	2,36E+09

© 2023 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com